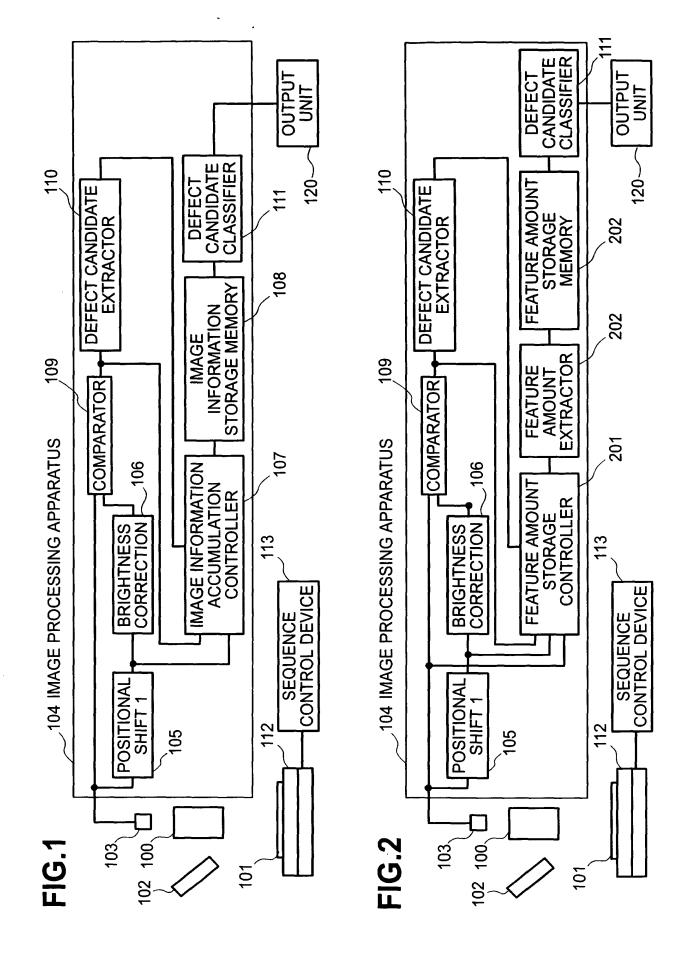
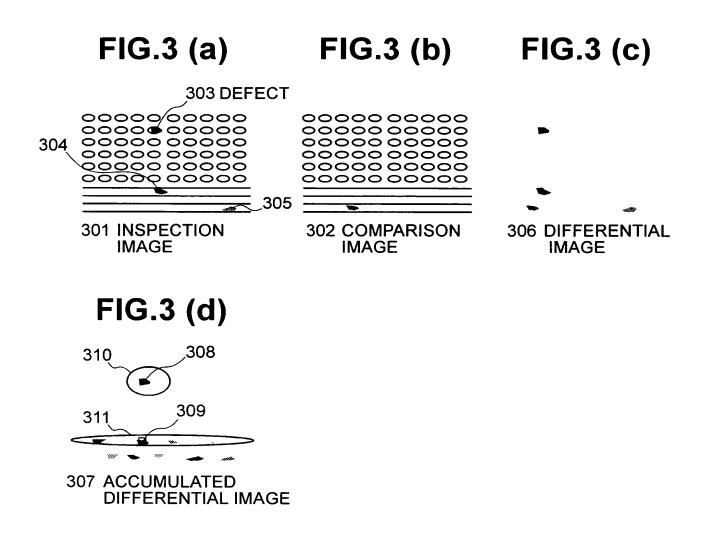
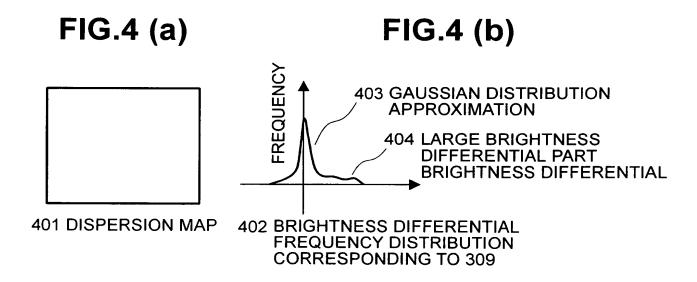
i,



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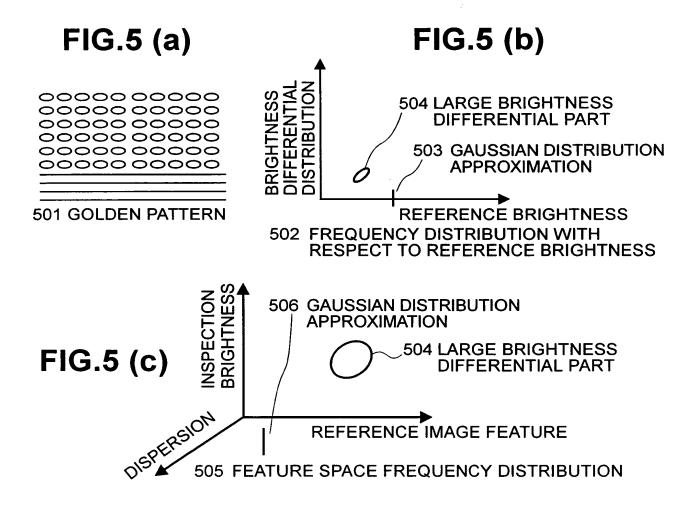


FIG.6

EXTRACTION OF DEFECT CANDIDATES AND LARGE DIFFERENTIAL IMAGE REGIONS.	
	SETTING OF GROUPING REGIONS PRODUCED BY GROUPING NEIGHBORING REGIONS ACCORDING TO DEFECT CANDIDATES AND LARGE DIFFERENTIAL IMAGE REGIONS.
FOR EACH DEFECT CANDIDATE	CALCULATION OF FEATURE AMOUNTS ON THE BASIS OF DIFFERENTIAL IMAGE BRIGHTNESS CORRECTED ACCORDING TO THE DISTRIBUTION OF THE DIFFERENTIAL IMAGE BRIGHTNESS OF THE GROUPING REGIONS TO WHICH THE DEFECT CANDIDATES BELONG.
	USING CALCULATED FEATURE AMOUNTS TO DETERMINE WHETHER THE DEFECT CANDIDATES ARE ACTUAL DEFECTS.

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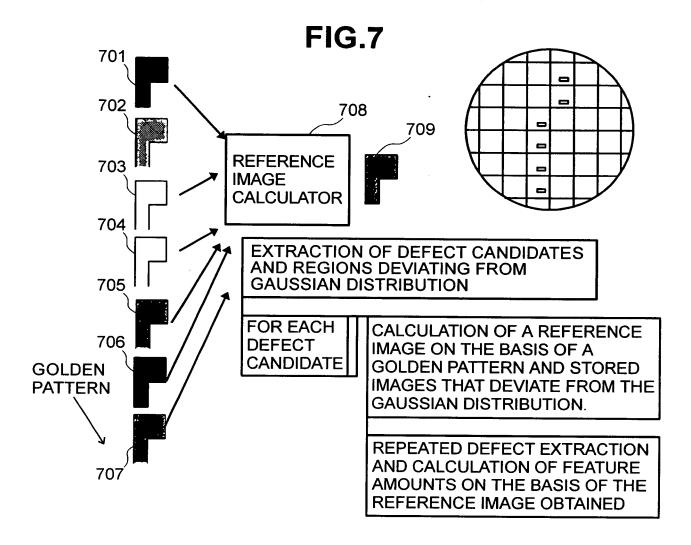
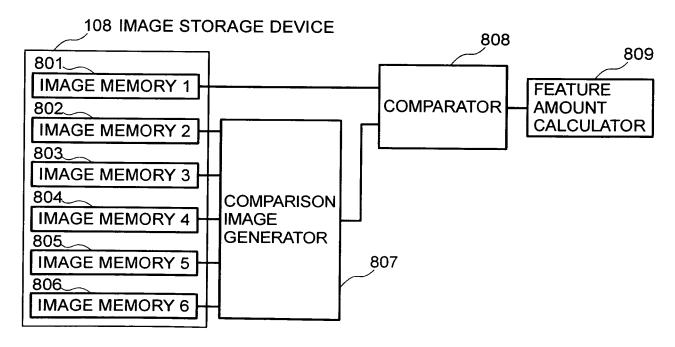
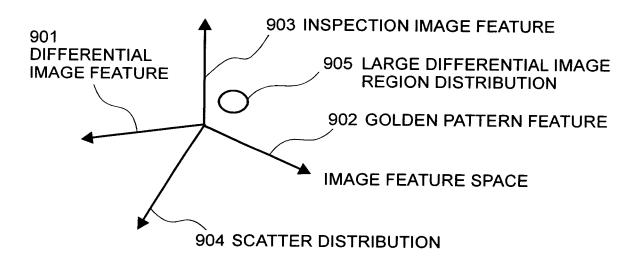


FIG.8



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FIG.9



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FIG.10

